# 高级通用串行总线收发器

查询样品: **TUSB1106-Q1**

特性

- 符合汽车应用要求
- 与通用串行总线规范 **2.0** 版兼容
- 在全速 **(12-Mbit/s)** 和低速 **(1.5-Mbit/s)** 速率发送和接收串行数据
- 集成 **5-V** 至 **3.3-V** 电压调节器用于通过 V_{BUS}
- V_{BUS} 通过 V_P 和 V_M的断开指示
- 用作**USB**设备收发器或者**USB**主机收发器
- 在**SE0**条件下的稳定**RCV**输出
- **2** 个具有滞后功能的单端接收器
- 是低功耗便携式设备的理想选择
- 支持 **I/O** 电压范围为 **1.65 V** 至 **3.6 V**
- 封装方式为超薄紧缩小型封装 **[TSSOP (PW)]**

PW 封装
（顶视图）

$V_{pu(3.3)}$	1	16 $V_{CC(5.0)}$
SOFTCON	2	15 $V_{reg(3.3)}$
$\overline{OE}$	3	14 VMO
RCV	4	13 VPO
VP	5	12 D+
VM	6	11 D−
SUSPND	7	10 SPEED
GND	8	9 $V_{CC(I/O)}$
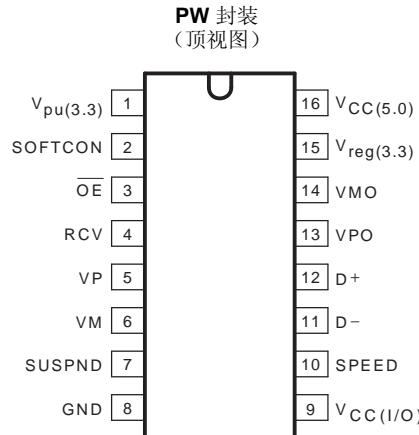
说明

TUSB1106-Q1 通用串行总线 (USB) 收发器与通用串行总线规范版本 2.0 兼容。 在全速 (12-Mbit/s) 和低速 (1.5-Mbit/s) 数据速率下，此设备都能发送和接收串行数据。 TUSB1106-Q1 能被用作USB设备收发器或者USB主机收发器。

此设备允许USB专用 IC （ASIC）和可编程逻辑设备 (PLD), 具有 1.65 V 至 3.6 V的电源供电电压, 到通用串行总线的物理层接口。 它是集成的 5-V 至 3.3-V 电压调节器，用于通过USB电源VBUS进行直接供电。

TUSB1106-Q1 只允许差分输入模式，封装方式为PW封装。

TUSB1106-Q1 是便携式电子设备，例如手机、个人数字助理、信息装置和数码相机的理想选择。

ORDERING INFORMATION

T_A	PACKAGE[1] [2]		ORDERABLE PART NUMBER	TOP-SIDE MARKING
−40°C to 85°C	TSSOP – PW	Reel of 2000	TUSB1106IPWRQ1	TU1106I

(1) Package drawings, thermal data, and symbolization are available at www.ti.com/packaging.
(2) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.

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FUNCTIONAL BLOCK DIAGRAM
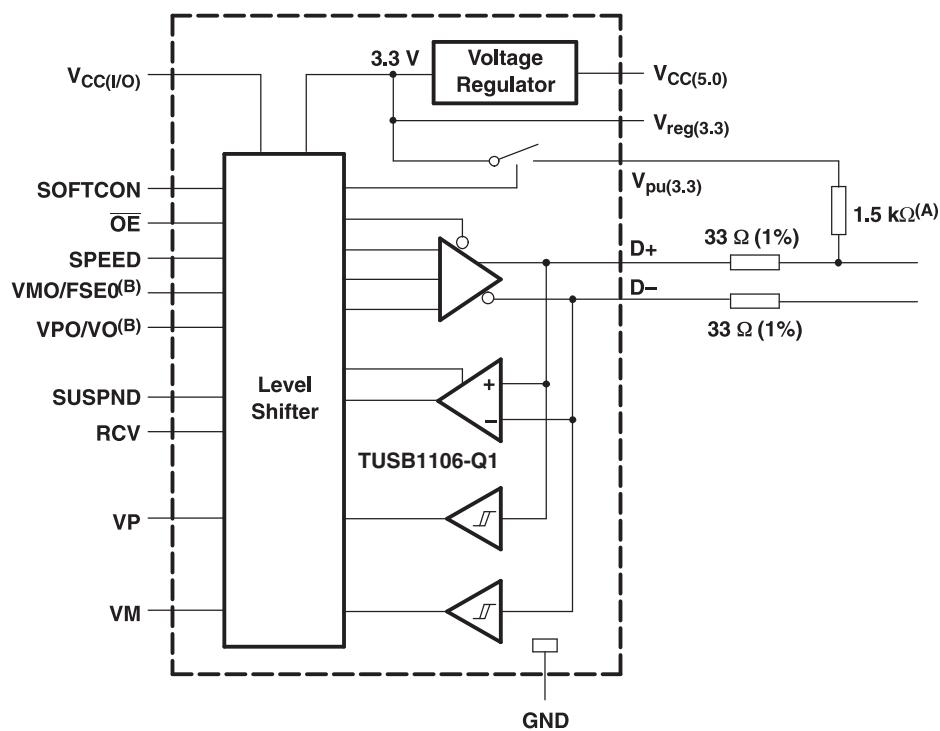
A. Connect to D– for low-speed operation and to D+ for high-speed operation.

B. Pin function depends on device type.

TERMINAL FUNCTIONS

TERMINAL		I/O	DESCRIPTION
NAME	NO.		
$\overline{OE}$	3	I	Output enable (CMOS level with respect to $V_{CC(I/O)}$, active LOW). Enables the transceiver to transmit data on the USB bus input pad. Push pull, CMOS.
RCV	4	O	Differential data receiver (CMOS level with respect to $V_{CC(I/O)}$). Driven LOW when input SUSPND is HIGH. The output state of RCV is preserved and stable during an SE0 condition output pad. Push pull, 4-mA output drive, CMOS.
VP	5	O	Single-ended D+ receiver (CMOS level with respect to V). For external detection of single-ended zero (SE0), error conditions, speed of connected device. Driven HIGH when no supply voltage is connected to $V_{CC(5.0)}$ and $V_{reg(3.3)}$ output pad. Push pull, 4-mA output drive, CMOS.
VM	6	O	Single-ended D– receiver (CMOS level with respect to $V_{CC(I/O)}$). For external detection of single-ended zero (SE0), error conditions, speed of connected device. Driven HIGH when no supply voltage is connected to $V_{CC(5.0)}$ and $V_{reg(3.3)}$ output pad. Push pull, 4-mA output drive, CMOS.
SUSPND	7	I	Suspend (CMOS level with respect to $V_{CC(I/O)}$). A HIGH level enables low-power state while the USB bus is inactive and drives output RCV to a LOW-level input pad. Push pull, CMOS.
MODE		I	Mode (CMOS level with respect to $V_{CC(I/O)}$). A HIGH level enables the differential input mode (VPO, VMO), whereas a LOW level enables a single-ended input mode (VO, FSE0). See Table 5 and Table 6 input pad. Push pull, CMOS.
GND	8		Ground supply
$V_{CC(I/O)}$	9		Supply voltage for digital I/O pins (1.65 to 3.6 V). When $V_{CC(I/O)}$ is not connected, the D+ and D– pins are in 3-state. This supply pin is independent of $V_{CC(5.0)}$ and $V_{reg(3.3)}$ and must never exceed the $V_{reg(3.3)}$ voltage.
SPEED	10	I	Speed selection (CMOS level with respect to $V_{CC(I/O)}$). Adjusts the slew rate of differential data outputs D+ and D– according to the transmission speed. Input pad, push pull, CMOS. LOW – low speed (1.5 Mbit/s) HIGH – full speed (12 Mbit/s)
D–	11	AI/O	Negative USB data bus connection (analog, differential). For low-speed mode, connect to pin $V_{pu(3.3)}$ via a 1.5-kΩ resistor.
D+	12	AI/O	Positive USB data bus connection (analog, differential). For full-speed mode, connect to pin $V_{pu(3.3)}$ via a 1.5-kΩ resistor.
VPO/VO		I	Driver data (CMOS level with respect to $V_{CC(I/O)}$, Schmitt trigger). See Driving Function table. Push pull, CMOS.
VPO	13		
VMO/FSE0		I	Driver data (CMOS level with respect to $V_{CC(I/O)}$, Schmitt trigger). See Driving Function table. Push pull, CMOS.
VMO	14		
$V_{reg(3.3)}$	15		Internal regulator option. Regulated supply-voltage output (3 V to 3.6 V) during 5-V operation. A decoupling capacitor of at least 0.1 mF is required for the regulator bypass option. Used as a supply-voltage input for 3.3 V ± 10% operation.
$V_{CC(5.0)}$	16		Internal regulator option. Supply-voltage input (4 V to 5.5 V). Can be connected directly to USB supply VBUS regulator bypass option. Connect to $V_{reg(3.3)}$.
$V_{pu(3.3)}$	1		Pullup supply voltage (3.3 V ± 10%). Connect an external 1.5-kΩ resistor on D+ (full speed) or D– (low speed). Pin function is controlled by input SOFTCON. SOFTCON = LOW – $V_{pu(3.3)}$ floating (high impedance), ensures zero pullup current SOFTCON = HIGH – $V_{pu(3.3)}$ = 3.3 V, internally connected to $V_{reg(3.3)}$
SOFTCON	2	I	Software-controlled USB connection. A HIGH level applies 3.3 V to pin $V_{pu(3.3)}$, which is connected to an external 1.5-kΩ pullup resistor. This allows USB connect/disconnect signaling to be controlled by software input pad. Push pull, CMOS.

FUNCTIONAL DESCRIPTION

Function Selection

FUNCTION TABLE

SUSPND	$\overline{OE}$	D+, D–	RCV	VP, VM	FUNCTION
L	L	Driving and receiving	Active	Active	Normal driving (differential receiver active)
L	H	Receiving[1]	Active	Active	Receiving
H	L	Driving	Inactive[2]	Active	Driving during suspend[3] (differential receiver inactive)
H	H	High-Z[1]	Inactive[2]	Active	Low-power state

(1) Signal levels on D+ and D– are determined by other USB devices and external pullup/pulldown resistors.
(2) In suspend mode (SUSPND = HIGH) the differential receiver is inactive and output RCV is always LOW. Out of suspend (K), signaling is detected via the single-ended receivers VP and VM.
(3) During suspend, the slew-rate control circuit of low-speed operation is disabled. The D+ and D– lines are still driven to their intended states, without slew-rate control. This is permitted because driving during suspend is used to signal remote wakeup by driving a K signal (one transition from idle to K state) for a period of 1 ms to 15 ms.

Operating Functions

Driving Function (Pin $\overline{OE}$ = L)
Using Differential Input Data Interface

VMO	VPO	DATA	DATA STATE	
			LOW SPEED	FULL SPEED
L	L	SE0	X	X
H	L	Differential logic 0	J	K
L	H	Differential logic 1	K	J
H	H	Illegal state	X	X

Table 1. Receiving Function (Pin $\overline{OE}$ = H)

D+, D–	RCV	VP[1]	VM[1]	DATA STATE	
				LOW SPEED	FULL SPEED
Differential logic 0	L	L	H	J	K
Differential logic 1	H	H	L	K	J
SE0	RCV*[2]	L	L	X	X

(1) VP = VM = H indicates the sharing mode ($V_{CC(5.0)}$ and $V_{reg(3.3)}$ are disconnected).
(2) RCV* denotes the signal level on output RCV just before SE0 state occurs. This level is stable during the SE0 period.

Power-Supply Configurations

The TUSB1106-Q1 can be used with different power-supply configurations, which can be dynamically changed. An overview is given in Table 3.

*   Normal mode – Both $V_{CC(I/O)}$ and $V_{CC(5.0)}$ or ($V_{CC(5.0)}$ and $V_{reg(3.3)}$) are connected. For 5-V operation, $V_{CC(5.0)}$ is connected to a 5-V source (4 V to 5.5 V). The internal voltage regulator then produces 3.3 V for the USB connections. For 3.3-V operation, both $V_{CC(5.0)}$ and $V_{reg(3.3)}$ are connected to a 3.3-V source (3 V to 3.6 V). $V_{CC(I/O)}$ is independently connected to a voltage source (1.65 V to 3.6 V), depending on the supply voltage of the external circuit.

*   Disable mode – $V_{CC(I/O)}$ is not connected, $V_{CC(5.0)}$ or ($V_{CC(5.0)}$ and $V_{reg(3.3)}$) are connected. In this mode, the internal circuits of the TUSB1106-Q1 ensure that the D+ and D– pins are in 3-state and the power consumption drops to the low-power (suspended) state level. Some hysteresis is built into the detection of $V_{CC(I/O)}$ lost.

*   Sharing mode – $V_{CC(I/O)}$ is connected, ($V_{CC(5.0)}$ and $V_{reg(3.3)}$) are not connected. In this mode, the D+ and D– pins are made 3-state and the TUSB1106-Q1 allows external signals of up to 3.6 V to share the D+ and D–

lines. The internal circuits of the TUSB1106-Q1 ensure that virtually no current (maximum 10 μA) is drawn via the D+ and D– lines. The power consumption through $V_{CC(I/O)}$ drops to the low-power (suspended) state level. Both the VP and VM pins are driven HIGH to indicate this mode. Pin RCV is made LOW. Some hysteresis is built into the detection of $V_{reg(3.3)}$ lost.

Table 2. Pin States in Disable or Sharing Mode

PINS	DISABLE-MODE STATE	SHARING-MODE STATE
$V_{CC(5.0)}$/$V_{reg(3.3)}$	5-V input/3.3-V output, 3.3-V input/3.3-V input	Not present
$V_{CC(I/O)}$	Not present	1.65-V to 3.6-V input
$V_{pu(3.3)}$	High impedance (off)	High impedance (off)
D+, D–	High impedance	High impedance
VP, VM	Invalid[1]	H
RCV	Invalid[2]	L
Inputs (VO/VPO, FSE0/VMO, SPEED, SUSPND, OE, SOFTCON)	High impedance	High impedance

(1)   High impedance or driven LOW
(2)   High impedance or driven LOW

Table 3. Power-Supply Configuration Overview

$V_{CC(5.0)}$ or $V_{reg(3.3)}$	$V_{CC(I/O)}$	CONFIGURATION	SPECIAL CHARACTERISTICS
Connected	Connected	Normal mode	
Connected	Not connected	Disable mode	D+, D–, and $V_{pu(3.3)}$ are in high impedance. VP, VM, and RCV are invalid.[1]
Not connected	Connected	Sharing mode	D+, D–, and $V_{pu(3.3)}$ are in high impedance. VP and VM are driven HIGH. RCV is driven LOW.

(1)   High impedance or driven LOW

Power-Supply Input Options

The TUSB1106-Q1 has two power-supply input options.

- Internal regulator – $V_{CC(5.0)}$ is connected to 4 V to 5.5 V. The internal regulator is used to supply the internal circuitry with 3.3 V (nominal). $V_{reg(3.3)}$ becomes a 3.3-V output reference.
- Regulator bypass – $V_{CC(5.0)}$ and $V_{reg(3.3)}$ are connected to the same supply. The internal regulator is bypassed and the internal circuitry is supplied directly from the $V_{reg(3.3)}$ power supply. The voltage range is 3 V to 3.6 V to comply with the USB specification.

The supply-voltage range for each input option is specified in Table 4.

Table 4. Power-Supply Input Options

INPUT OPTION	$V_{CC(5.0)}$	$V_{REG(3.3)}$	$V_{CC(I/O)}$
Internal regulator	Supply input for internal regulator (4 V to 5.5 V)	Voltage-reference output (3.3 V, 300 μA)	Supply input for digital I/O pins (1.65 V to 3.6 V)
Regulator bypass	Connected to $V_{reg(3.3)}$ with maximum voltage drop of 0.3 V (2.7 V to 3.6 V)	Supply input (3 V to 3.6 V)	Supply input for digital I/O pins (1.65 V to 3.6 V)

ABSOLUTE MAXIMUM RATINGS[1]

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
$V_{CC(5.0)}$	Supply voltage range		–0.5	6	V
$V_{I(I/O)}$	Supply voltage range		–0.5	4.6	V
$V_{CCreg(3.3)}$	Regulated voltage range		–0.5	4.6	V
V_I	DC input voltage		–0.5	$V_{CC(I/O)}$ + 0.5	V
I_{IK}	Input clamp current	V_I = –1.8 V to 5.4 V		100	mA
T_{stg}	Storage temperature range		–40	125	°C

(1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

RECOMMENDED OPERATING CONDITIONS

			MIN	NOM	MAX	UNIT
$V_{CC(5.0)}$	Supply voltage, internal regulator option	5-V operation	4	5	5.5	V
$V_{CCreg(3.3)}$	Supply voltage, regulator bypass option	3.3-V operation	3	3.3	3.6	V
$V_{CC(I/O)}$	I/O supply voltage		1.65		3.6	V
V_I	I/O supply voltage		0		$V_{CC(I/O)}$	V
$V_{I/O}$	Input voltage on analog I/O pins (D+, D–)		0		3.6	V
T_c	Junction temperature		–40		85	°C

STATIC ELECTRICAL CHARACTERISTICS – SUPPLY PINS

over recommended ranges of operating free-air temperature and supply voltage (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
$V_{reg(3.3)}$	Regulated supply-voltage output	Internal regulator option, $I_{load} ≤ 300$ µA[1] [2]		3	3.3	3.6	V
I_{CC}	Operating supply current	Full-speed transmitting and receiving at 12 Mbit/s, $C_L = 50$ pF on D+ and D–[3]			6	8	mA
$I_{CC(I/O)}$	Operating I/O supply current	Full-speed transmitting and receiving at 12 Mbit/s[3]			2.3	2.5	mA
$I_{CC(idle)}$	Supply current during full-speed idle and SE0	Full-speed idle: $V_{D+} > 2.7$ V, $V_{D–} < 0.3$ V SE0: $V_{D+} < 0.3$ V, $V_{D–} < 0.3$ V[4]				500	µA
$I_{CC(I/O)(static)}$	Static I/O supply current	Full-speed idle, SE0 or suspend			10	22	µA
$I_{CC(susp)}$	Suspend supply current	SUSPND = HIGH[4]			10	22	µA
$I_{CC(dis)}$	Disable-mode supply current	$V_{CC(I/O)}$ not connected[4]			10	22	µA
$I_{CC(I/O)(sharing)}$	Sharing-mode I/O supply current	$V_{CC(5.0)}$ or $V_{reg(3.3)}$ not connected			10	22	µA
$I_{Dx(sharing)}$	Sharing-mode load current on D+ and D–	$V_{CC(5.0)}$ or $V_{reg(3.3)}$ not connected, SOFTCON = LOW, $V_{Dx} = 3.6$ V				10	µA
$V_{reg(3.3)th}$	Regulated supply-voltage detection threshold	1.65 V ≤ $V_{CC(I/O)}$ ≤ $V_{reg(3.3)}$, 2.7 V ≤ $V_{reg(3.3)}$ ≤ 3.6 V	Supply lost during power down			0.8	V
			Supply detect during power up[5]	2.4			
$V_{reg(3.3)hys}$	Regulated supply-voltage detection hysteresis	$V_{CC(I/O)} = 1.8$ V			0.45		V
$V_{CC(I/O)th}$	I/O supply-voltage detection threshold	$V_{reg(3.3)} = 2.7$ V to 3.6 V	Supply lost during power down			0.5	V
			Supply detect during power up	1.4			
$V_{CC(I/O)hys}$	I/O supply-voltage detection hysteresis	$V_{reg(3.3)} = 3.3$ V			0.45		V

(1) I_{load} includes the pullup resistor current via $V_{pu(3.3)}$.
(2)   In suspend mode, the typical voltage is 2.8 V.
(3)   Maximum value is characterized only, not tested in production.
(4)   Excluding any load current and $V_{pu(3.3)}$/V_{sw} source current to the 1.5-kΩ and 15-kΩ pullup and pulldown resistors (200 µA typ)
(5)   When $V_{CC(I/O)} < 2.7$ V, the minimum value for $V_{reg(3.3)th}$ (present) is 2 V.

STATIC ELECTRICAL CHARACTERISTICS – DIGITAL PINS

over recommended ranges of operating free-air temperature and supply voltage (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	$V_{CC(I/O)}$	MIN	MAX	UNIT
V_{IL}	LOW-level input voltage		1.65 V to 3.6 V		$0.3\ V_{CC(I/O)}$	V
V_{IH}	HIGH-level input voltage		1.65 V to 3.6 V	$0.6\ V_{CC(I/O)}$		V
V_{OL}	LOW-level output voltage	I_{OL} = 100 µA	1.65 V to 3.6 V		0.15	V
		I_{OL} = 2 mA			0.4	
		I_{OL} = 100 µA	1.8 V ± 0.15 V		0.15	
		I_{OL} = 2 mA			0.4	
		I_{OL} = 100 µA	2.5 V ± 0.2 V		0.15	
		I_{OL} = 2 mA			0.4	
		I_{OL} = 100 µA	3.3 V ± 0.3 V		0.15	
		I_{OL} = 2 mA			0.4	
V_{OH}	HIGH-level output voltage	I_{OH} = 100 µA	1.65 V to 3.6 V	$V_{CC(I/O)} - 0.15$		V
		I_{OH} = 2 mA		$V_{CC(I/O)} - 0.4$		
		I_{OH} = 100 µA	1.8 V ± 0.15 V	1.5		
		I_{OH} = 2 mA		1.25		
		I_{OH} = 100 µA	2.5 V ± 0.2 V	2.15		
		I_{OH} = 2 mA		1.9		
		I_{OH} = 100 µA	3.3 V ± 0.3 V	2.85		
		I_{OH} = 2 mA		2.6		
I_{LI}	Input leakage current			−1	1	µA
C_{IN}	Input capacitance	Pin to GND			3.5	pF

STATIC ELECTRICAL CHARACTERISTICS – ANALOG I/O PINS

over recommended ranges of operating free-air temperature and supply voltage, V_{CC} = 4 V to 5.5 V or $V_{reg(3.3)}$ = 3 V to 3.6 V, V_{GND} = 0 V, T_A = –40°C to 85°C (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
V_{DI}	Differential input sensitivity	$|V_{I(D+)} - V_{I(D-)}|$	0.2			V
V_{CM}	Differential common-mode voltage	Includes V_{DI} range	0.8		2.5	V
V_{IL}	LOW-level input voltage, single-ended receiver		2		0.8	V
V_{IH}	HIGH-level input voltage, single-ended receiver		0.4			V
V_{hys}	Hysteresis voltage, single-ended receiver				0.7	V
V_{OL}	LOW-level output voltage	R_L = 1.5 kΩ to 3.6 V			0.3	V
V_{OH}	HIGH-level output voltage	R_L = 1.5 kΩ to GND	2.8[1]		3.6	V
I_{LZ}	OFF-state leakage current				1	µA
C_{IN}	Transceiver capacitance	Pin to GND			25	pF
Z_{DRV}	Driver output impedance	Steady-state drive	34[2]	39	44	Ω
Z_{INP}	Input impedance		10			MΩ
R_{SW}	Internal switch resistance at $V_{pu(3.3)}$				13	Ω
V_{TERM}	Termination voltage for upstream port pullup (RPU)		3[3] [4]		3.6	V

(1) $V_{OH(min)}$ = $V_{reg(3.3)}$ – 0.2 V
(2) Includes external resistors of 33 Ω ±1% on both D+ and D–
(3) This voltage is available at $V_{reg(3.3)}$ and $V_{pu(3.3)}$.
(4) In suspend mode, the minimum voltage is 2.7 V.

DYNAMIC ELECTRICAL CHARACTERISTICS – ANALOG I/O PINS (D+, D–)[1] [2]
Driver Characteristics, Full-Speed Mode

over recommended ranges of operating free-air temperature and supply voltage, V_{CC} = 4 V to 5.5 V or $V_{reg(3.3)}$ = 3 V to 3.6 V, $V_{CC(I/O)}$ = 1.65 V to 3.6 V, V_{GND} = 0 V, see Table 10 for valid voltage level combinations, T_A = –40°C to 85°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	MAX	UNIT
t_{FR}	Rise time	C_L = 50 pF to 125 pF, 10% to 90% of $\lvert V_{OH} - V_{OL} \rvert$ (see Figure 1)	4	20	ns
t_{FF}	Fall time	C_L = 50 pF to 125 pF, 90% to 10% of $\lvert V_{OH} - V_{OL} \rvert$ (see Figure 1)	4	20	ns
FRFM	Differential rise/fall time matching (t_{FR}/t_{FF})	Excluding the first transition from idle state	90	111.1	%
V_{CRS}	Output signal crossover voltage	Excluding the first transition from idle state (see Figure 10)	1.3	2	V

(1) Test circuit, see Figure 13
(2) Driver timing in low-speed mode is not specified. Low-speed delay timings are dominated by the slow rise/fall times t_{LR} and t_{LF}.

DYNAMIC ELECTRICAL CHARACTERISTICS – ANALOG I/O PINS (D+, D–)[1] [2]
Driver Characteristics, Low-Speed Mode

over recommended ranges of operating free-air temperature and supply voltage, V_{CC} = 4 V to 5.5 V or $V_{reg(3.3)}$ = 3 V to 3.6 V, $V_{CC(I/O)}$ = 1.65 V to 3.6 V, V_{GND} = 0 V, see Table 10 for valid voltage level combinations, T_A = –40°C to 85°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	MAX	UNIT
t_{LR}	Rise time	C_L = 200 pF to 600 pF, 10% to 90% of $\lvert V_{OH} - V_{OL} \rvert$ (see Figure 1)	75	300	ns
t_{LF}	Fall time	C_L = 200 pF to 600 pF, 90% to 10% of $\lvert V_{OH} - V_{OL} \rvert$ (see Figure 1)	75	300	ns
LRFM	Differential rise/fall time matching (t_{LR}/t_{LF})	Excluding the first transition from idle state	80	125	%
V_{CRS}	Output signal crossover voltage	Excluding the first transition from idle state (see Figure 10)	1.3	2	V

(1) Test circuit, see Figure 13
(2) Driver timing in low-speed mode is not specified. Low-speed delay timings are dominated by the slow rise/fall times t_{LR} and t_{LF}.

DYNAMIC ELECTRICAL CHARACTERISTICS – ANALOG I/O PINS (D+, D–)[1] [2]
Driver Timing, Full-Speed Mode

over recommended ranges of operating free-air temperature and supply voltage, V_{CC} = 4 V to 5.5 V or $V_{reg(3.3)}$ = 3 V to 3.6 V, $V_{CC(I/O)}$ = 1.65 V to 3.6 V, V_{GND} = 0 V, see Table 10 for valid voltage level combinations, T_A = –40°C to 85°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	MAX	UNIT
$t_{PLH(drv)}$	Driver propagation delay (VO/VPO, FSE0/VMO to D+, D–)	LOW to HIGH (see Figure 4)		18	ns
$t_{PHL(drv)}$		HIGH to LOW (see Figure 4)		18	
t_{PHZ}	Driver disable delay ($\overline{OE}$ to D+, D–)	HIGH to OFF (see Figure 2)		15	ns
t_{PLZ}		LOW to OFF (see Figure 2)		15	
t_{PZH}	Driver enable delay ($\overline{OE}$ to D+, D–)	OFF to HIGH (see Figure 2)		15	ns
t_{PZL}		OFF to LOW (see Figure 2)		15	

(1) Test circuit, see Figure ?
(2) Driver timing in low-speed mode is not specified. Low-speed delay timings are dominated by the slow rise/fall times t_{LR} and t_{LF}.

DYNAMIC ELECTRICAL CHARACTERISTICS FOR ANALOG I/O PINS (D+, D–)[1]
Receiver Timing, Full-Speed and Low-Speed Mode, Differential Receiver

over recommended ranges of operating free-air temperature and supply voltage, V_{CC} = 4 V to 5.5 V or $V_{reg(3.3)}$ = 3 V to 3.6 V, $V_{CC(I/O)}$ = 1.65 V to 3.6 V, V_{GND} = 0 V, see Table 10 for valid voltage level combinations, T_A = –40°C to 85°C (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	MAX	UNIT
$t_{PLH(rcv)}$	Propagation delay (D+, D– to RCV)	LOW to HIGH (see Figure 3)		15	ns
$t_{PHL(rcv)}$		HIGH to LOW (see Figure 3)		15	

(1) Test circuit, see Figure ?

DYNAMIC ELECTRICAL CHARACTERISTICS FOR ANALOG I/O PINS (D+, D–)[1]
Receiver Timing, Full-Speed and Low-Speed Mode, Single-Ended Receiver

over recommended ranges of operating free-air temperature and supply voltage, V_{CC} = 4 V to 5.5 V or $V_{reg(3.3)}$ = 3 V to 3.6 V, $V_{CC(I/O)}$ = 1.65 V to 3.6 V, V_{GND} = 0 V, see Table 10 for valid voltage level combinations, T_A = –40°C to 85°C (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	MAX	UNIT
$t_{PLH(se)}$	Propagation delay (D+, D– to VP, VM)	LOW to HIGH (see Figure 3)		18	ns
$t_{PHL(se)}$		HIGH to LOW (see Figure 3)		18	

(1) Test circuit, see Figure 13
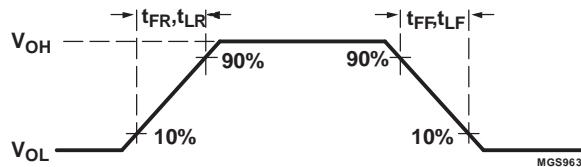
Figure 1. Rise and Fall Times
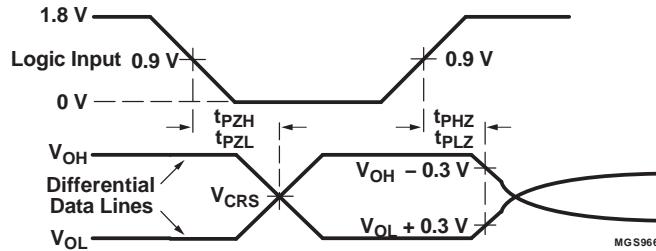
Figure 2. $\overline{OE}$ to D+, D–
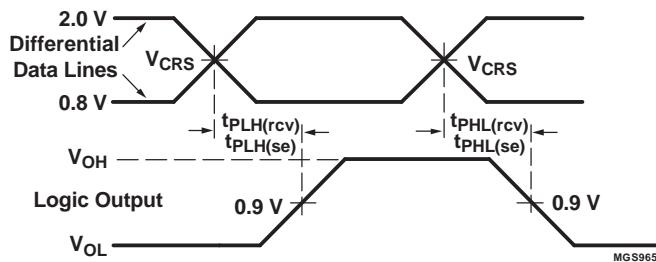
Figure 3. D+, D– to RCV, VP, VM
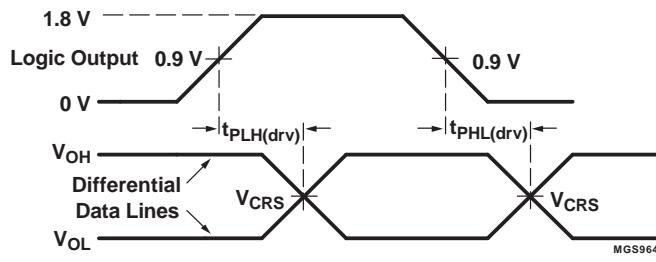
Figure 4. VO/VPO, FSE0/VMO to D+, D–

APPLICATION INFORMATION
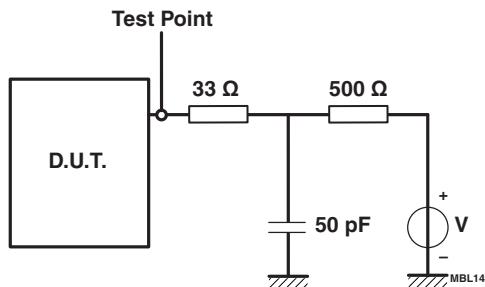
**Figure 5. Load for Enable and Disable Times**

A.   V = 0 V for t_{PZH}, t_{PHZ}

B.   V = $V_{reg(3.3)}$ for t_{PZL}, t_{PLZ}
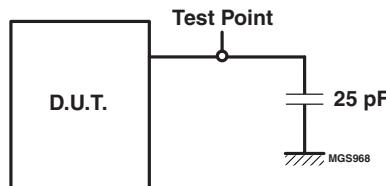
Figure 6. Load for VM, VP, and RCV
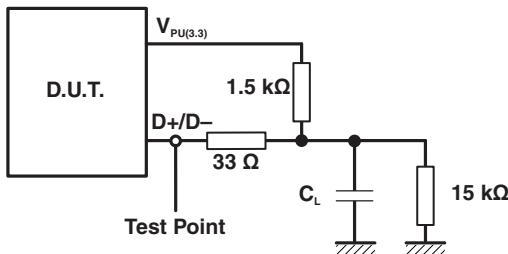
**Figure 7. Load for D+, D–**

A.   Full-speed mode: connected to D+

B.   Low-speed mode: Connected to D–

C.   Load capacitance:
   • C_L = 50 pF or 125 pF (full-speed mode, minimum or maximum timing)
   • C_L = 200 pF or 600 pF (low-speed mode, minimum or maximum timing)
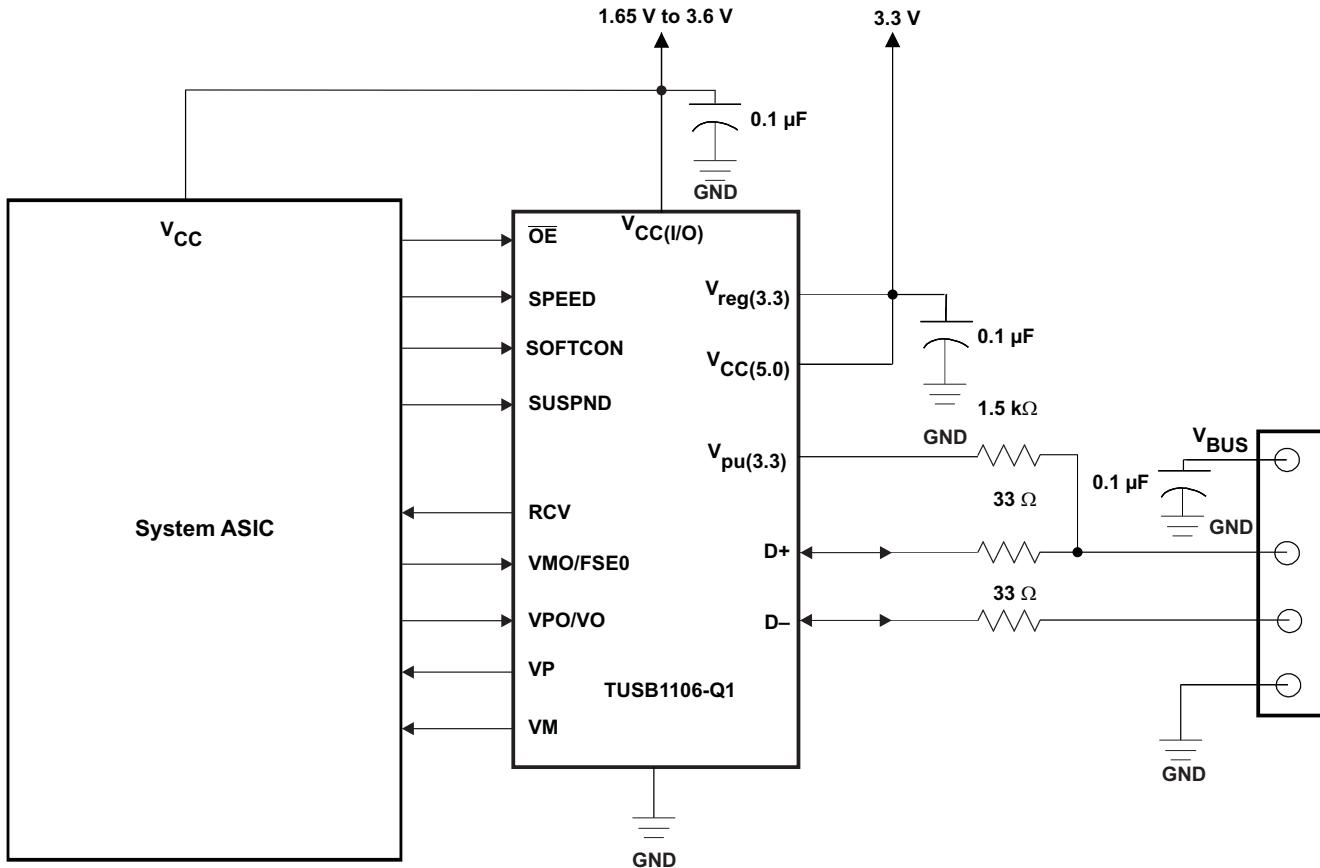
Figure 8. Peripheral-Side (Full-Speed) Regulator Bypass Mode

Peripheral-Side (Full-Speed) Regulator Bypass Mode

This mode is applicable when there is a 3.3-V supply already available on the board. The V_{BUS} pin of the USB connector, if left unused at the peripheral side, should be terminated with a 0.1-µF capacitor. While operating at full speed, the 1.5-kΩ resistor must be connected between the D+ line and $V_{PU(3.3)}$ or an external 3.3-V supply. When the $V_{CC(5.0)}$ and the $V_{reg(3.3)}$ are connected together, the device operates at regulator bypass mode. This enables power savings since the regulator is turned off.
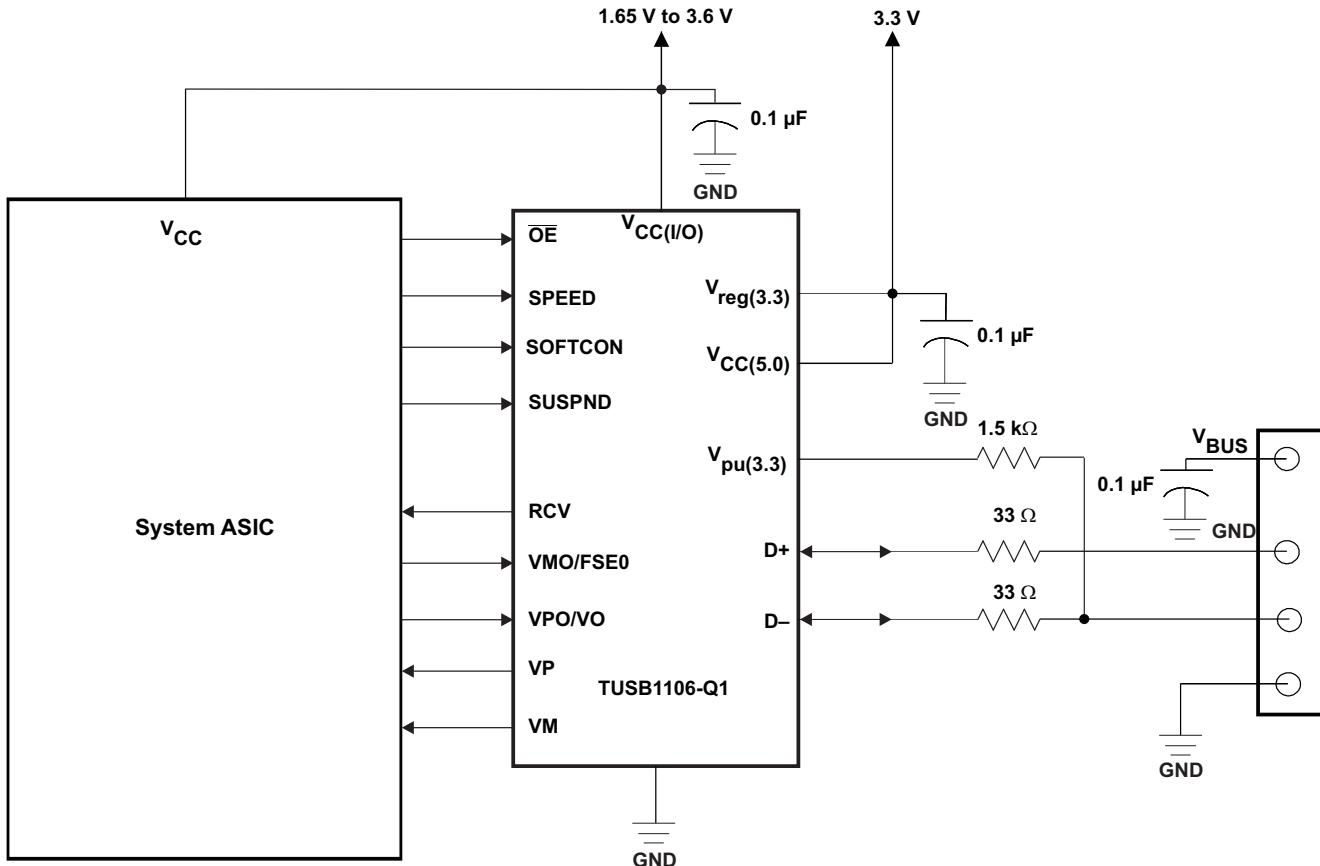
Figure 9. Peripheral-Side (Low-Speed) Regulator Bypass Mode

Peripheral-Side (Low-Speed) Regulator Bypass Mode

This mode is applicable when there is a 3.3-V supply already available on the board. The V_{BUS} pin of the USB connector, if left unused at the peripheral side, should be terminated with a 0.1-µF capacitor. While operating at low speed, the 1.5-kΩ resistor must to be connected between the D– line and $V_{PU(3.3)}$ or an external 3.3-V supply. When the $V_{CC(5.0)}$ and the $V_{reg(3.3)}$ are connected together, the device operates at regulator bypass mode. This enables power savings since the regulator is turned off.
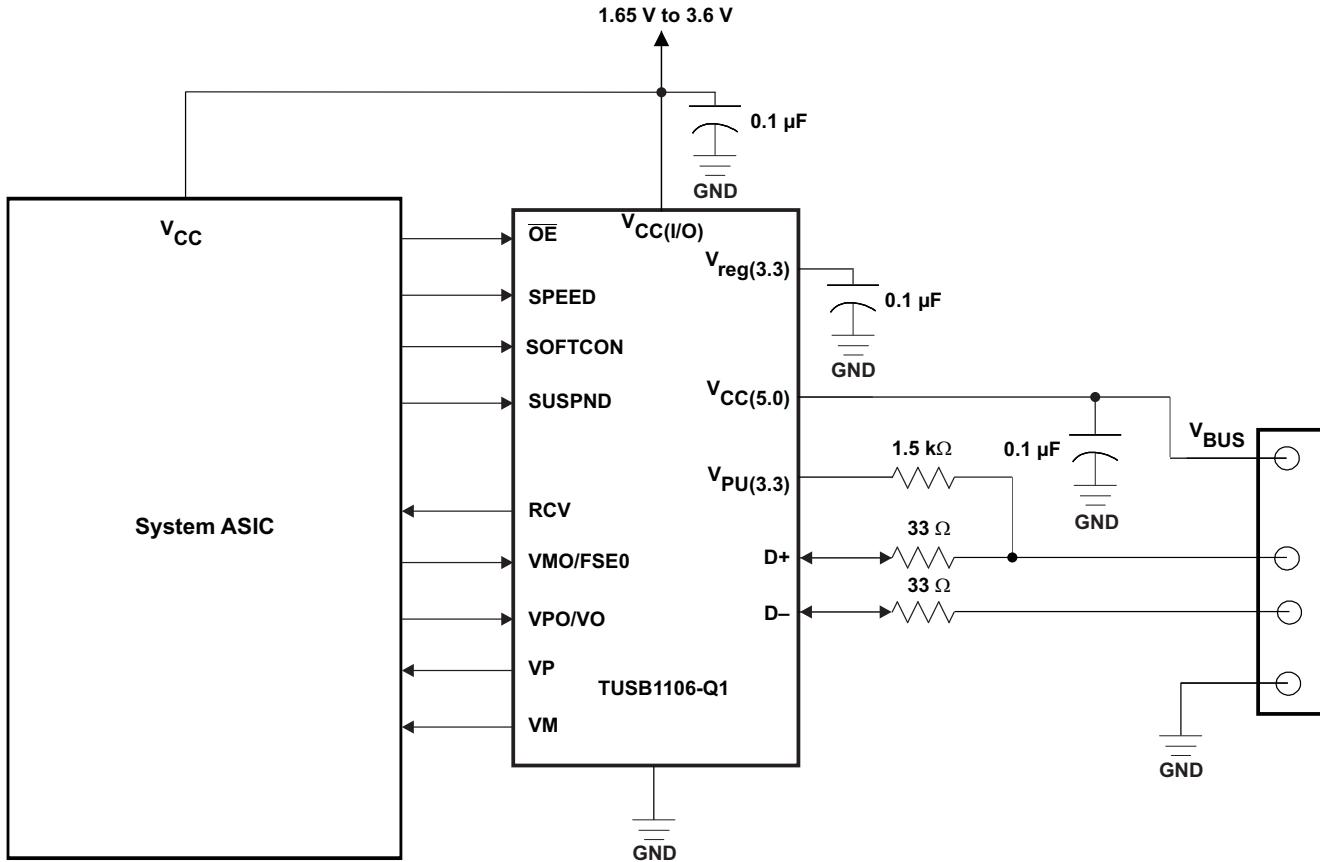
Figure 10. Peripheral-Side (Full-Speed) Internal Regulator Mode

Peripheral-Side (Full-Speed) Internal Regulator Mode

The USB side of the TUSB1106-Q1 can be powered from the V_{BUS} line directly if a 3.3-V supply is not present on board. In this case, the internal regulator can be used to provide the 3.3-V supply for USB signaling. The $V_{CC(5.0)}$ is connected to the V_{BUS}, which receives 5-V supply from the host, and generates the 3.3-V output at the $V_{reg(3.3)}$ pin. In this mode, it is important that both $V_{CC(5.0)}$ and $V_{reg(3.3)}$ pins have individual bypass capacitors in the range of 0.1 µF. Powering $V_{CC(5.0)}$ through the V_{BUS} port of the USB connector realizes significant power saving for portable applications, such as cell phones, PDAs, etc. In this operating mode, the $I_{CC(5.0)}$ current is fed from the host. The USB-side power consumption, $I_{CC(5.0)}$ is 4 mA (with the regulator active), as opposed to logic-side $I_{CC(IO)}$ of 1 mA under full-speed operation. While operating at full speed, the 1.5-kΩ resistor must be connected between the D+ line and the $V_{PU(3.3)}$ or an external 3.3-V supply.
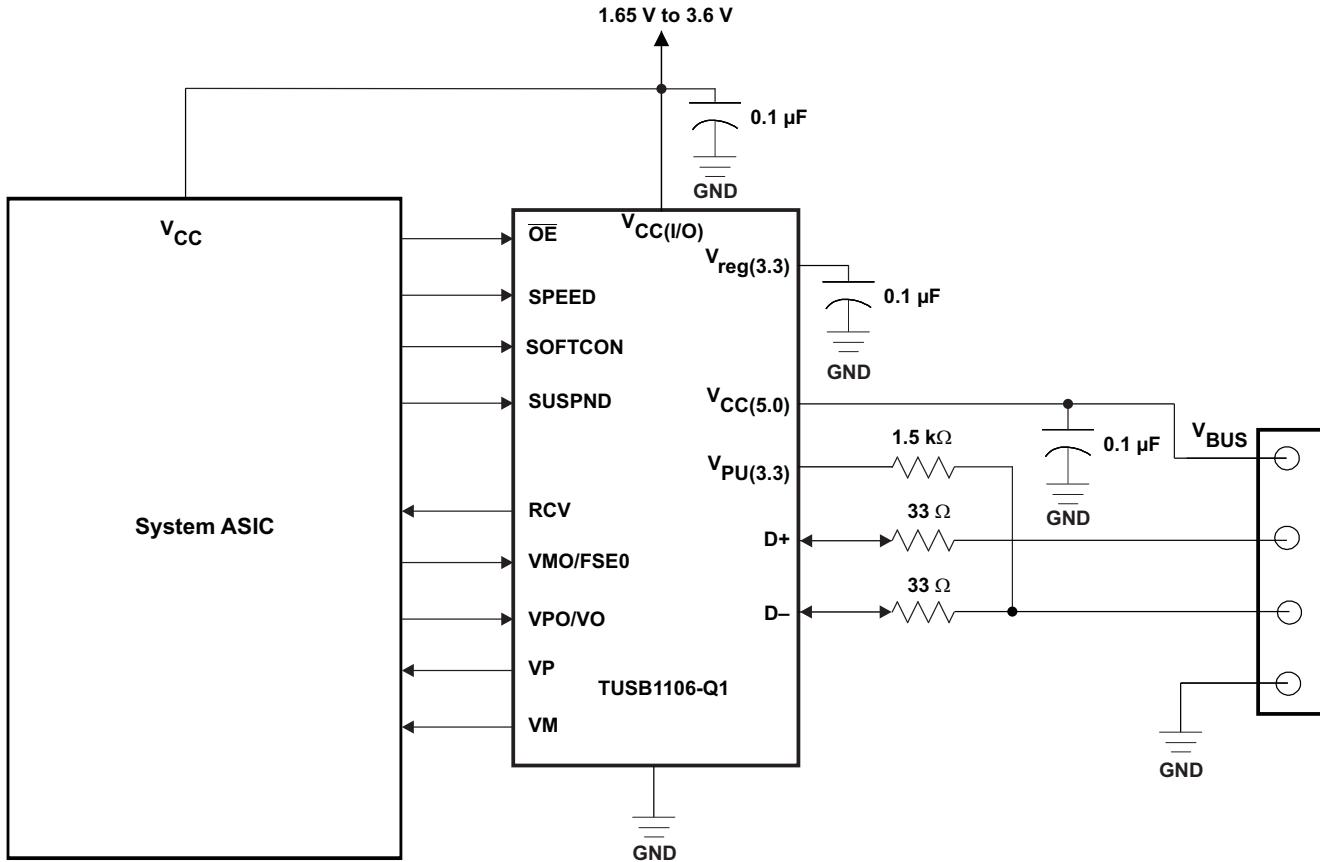
Figure 11. Peripheral-Side (Low-Speed) Internal Regulator Mode

Peripheral-Side (Low-Speed) Internal Regulator Mode

The USB side of the TUSB1106-Q1 can be powered from the V_{BUS} line directly if a 3.3-V supply is not present on board. In this case, the internal regulator can be used to provide the 3.3-V supply for the USB signaling. The $V_{CC(5.0)}$ is connected to the V_{BUS}, which receives 5-V supply from the host, and generates the 3.3-V output at the $V_{reg(3.3)}$ pin. In this mode, it is important that both $V_{CC(5.0)}$ and $V_{reg(3.3)}$ pins have individual bypass capacitors in the range of 0.1 μF. Powering $V_{CC(5.0)}$ through the V_{BUS} port of the USB connector realizes significant power saving for portable applications, such as cell phones, PDAs, etc. In this operating mode, the $I_{CC(5.0)}$ current is fed from the host side. The USB-side power consumption, $I_{CC(5.0)}$ is 4 mA (with the regulator active), as opposed to logic-side $I_{CC(IO)}$ of 1 mA under full-speed operation. While operating at low speed, the 1.5-kΩ resistor must be connected between the D– line and the $V_{PU(3.3)}$ or an external 3.3-V supply.
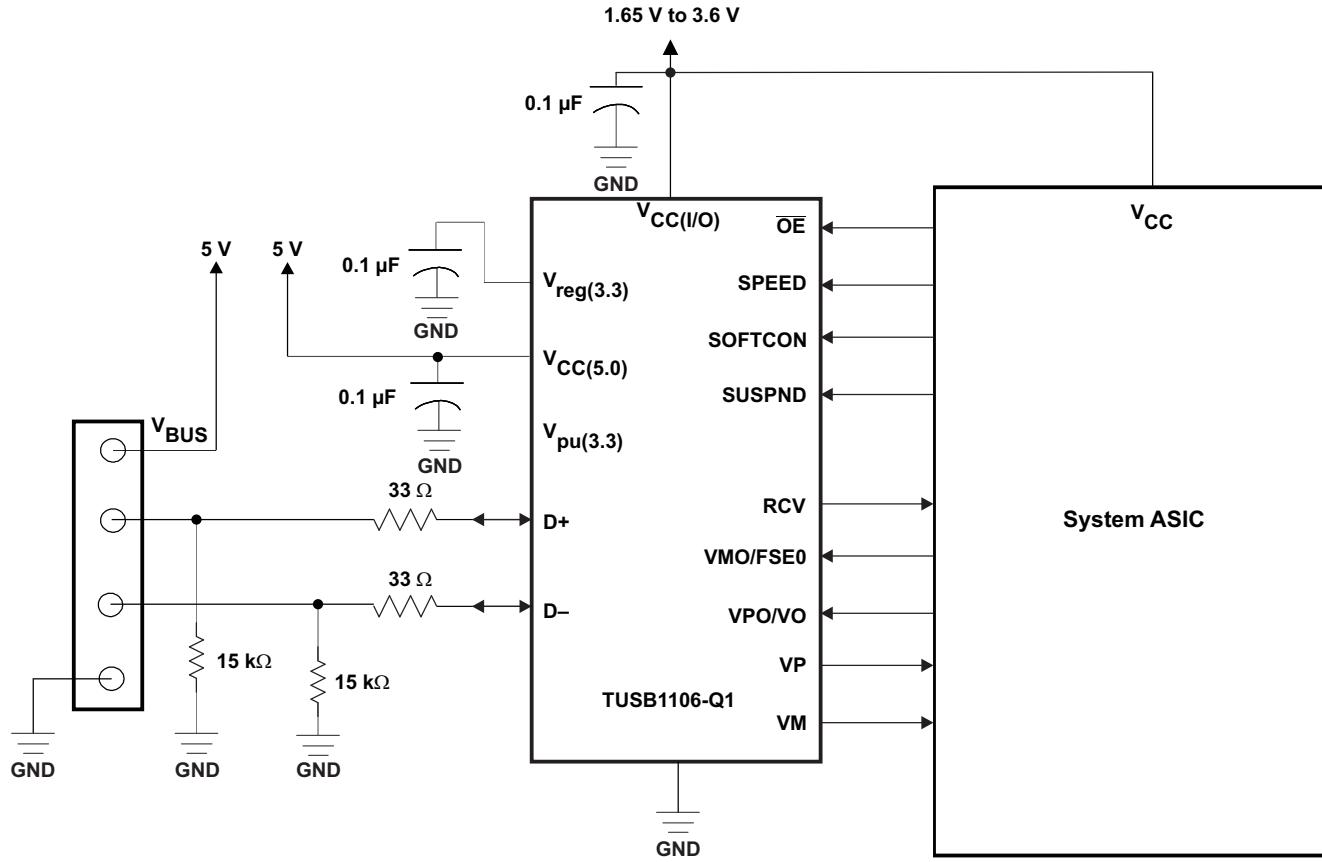
Figure 12. Host Side (V$_{CC(5.0)}$ Supplied From V$_{BUS}$ Pin)

Host Side (V$_{CC(5.0)}$ Supplied From V$_{BUS}$ Pin)

If there is no 3.3-V supply on board, an external 5-V supply can support the USB-side power needs. When the V$_{CC(5.0)}$ is connected to an external 5-V supply, the on-chip regulator generates the 3.3-V internal supply rail, which is used to drive the USB signaling levels at the USB side of the TUSB1106-Q1. The logic-side I/Os can operate at any voltage range from 1.65 V to 3.6 V.
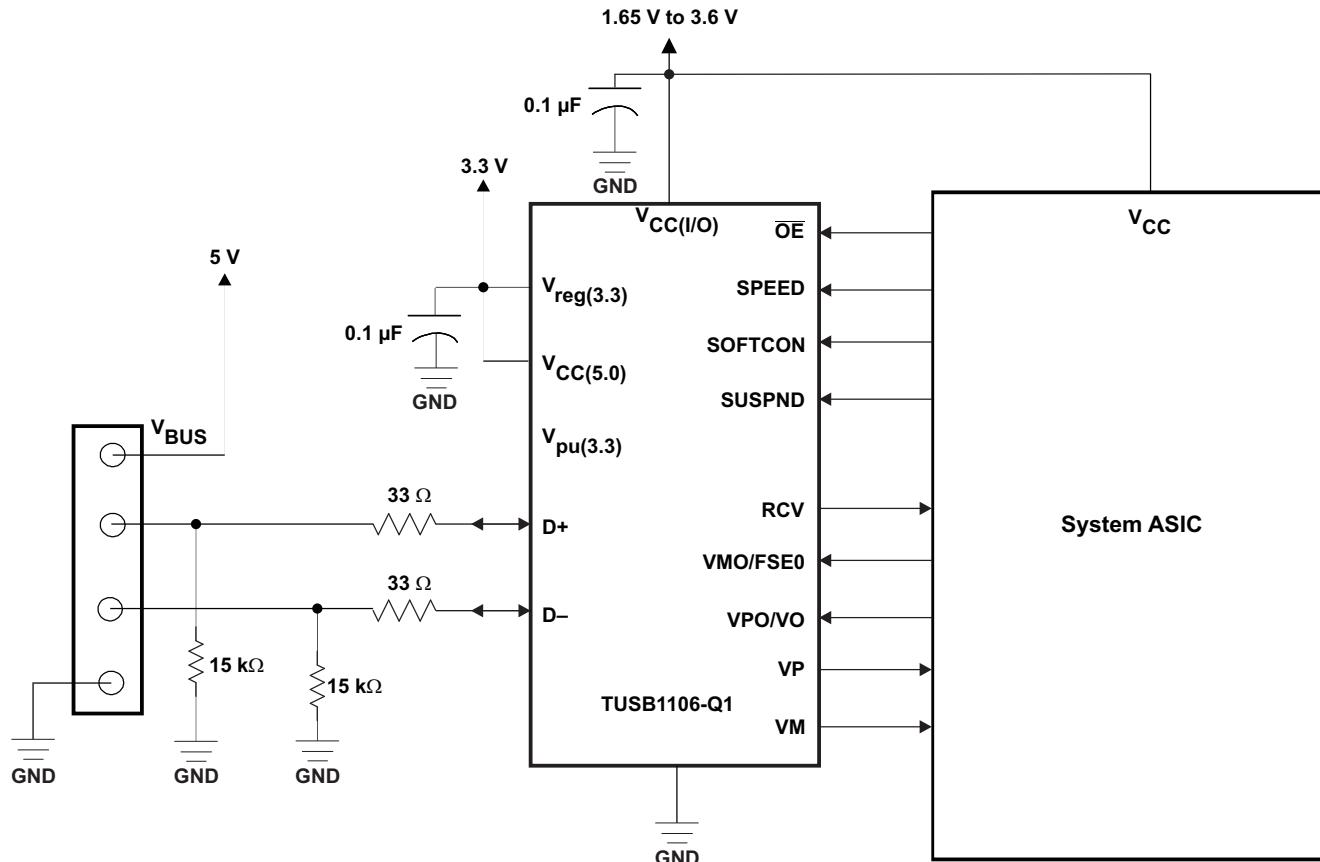
Figure 13. Host-Side (3.3-V Supply Present) Internal Regulator Bypass Mode

Host-Side (3.3-V Supply Present) Internal Regulator Bypass Mode

If a 3.3-V supply supports the USB-side power, $V_{CC(5.0)}$ and $V_{reg(3.3)}$ must to be tied together and connected to a 3.3-V supply. It also makes the regulator inactive.

PACKAGE OPTION ADDENDUM

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package | Pins	Package qty | Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
TUSB1106IPWRQ1	Active	Production	TSSOP (PW) | 16	2000 | LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TU1106I
TUSB1106IPWRQ1.A	Active	Production	TSSOP (PW) | 16	2000 | LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TU1106I

(1) Status: For more details on status, see our product life cycle.

(2) Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

(3) RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

(4) Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

(5) MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

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OTHER QUALIFIED VERSIONS OF TUSB1106-Q1 :

● Catalog : TUSB1106

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product

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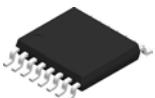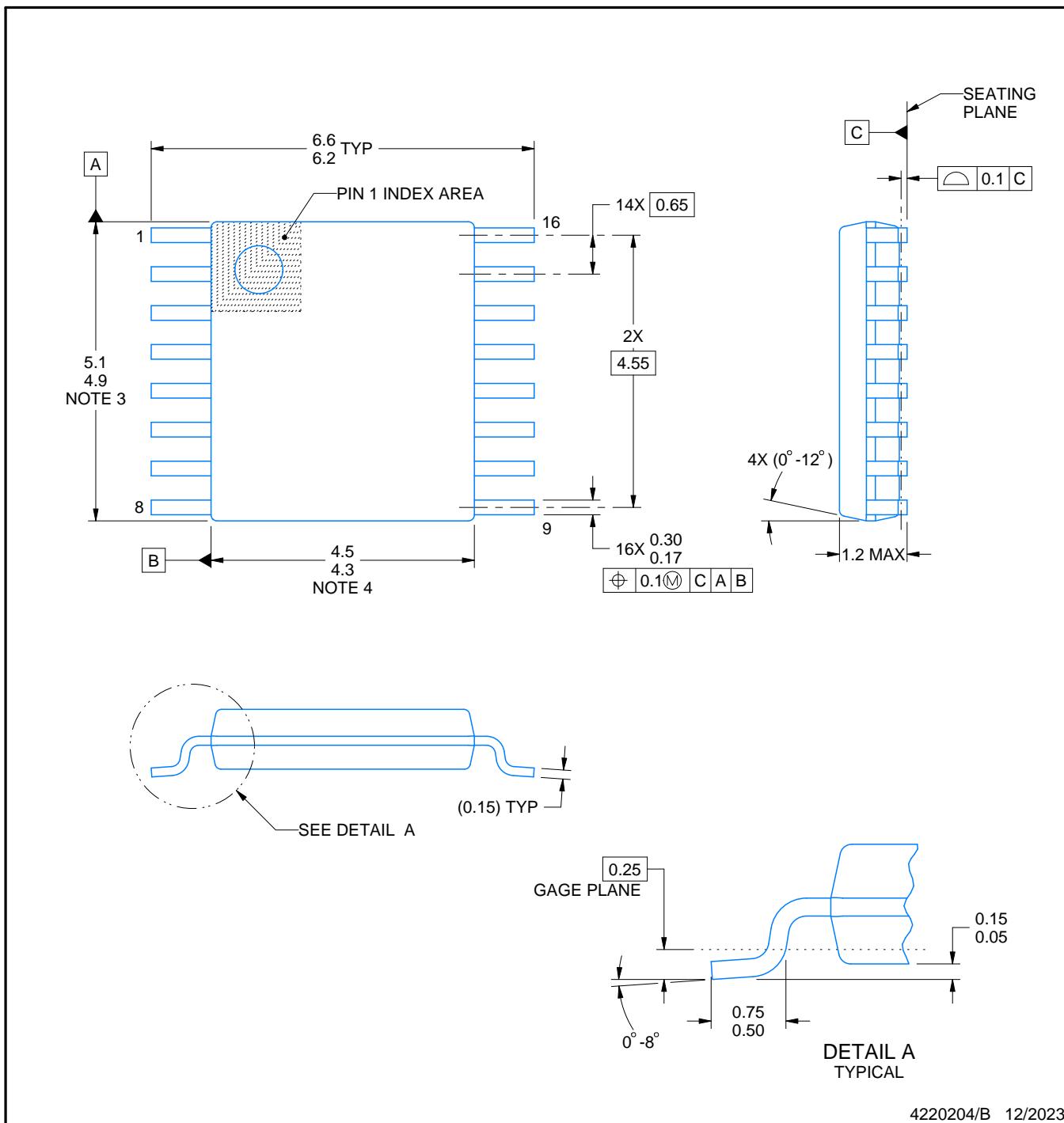
NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
5. Reference JEDEC registration MO-153.

16X (1.5)

SYMM

1

16X (0.45)

(R0.05) TYP

16

SYMM

14X (0.65)

8

9

(5.8)
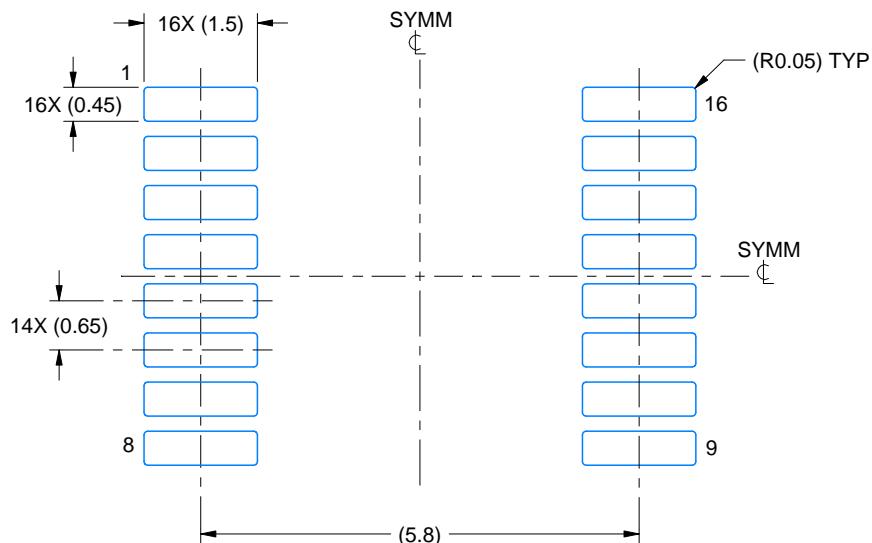
LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 10X

SOLDER MASK
OPENING

METAL

EXPOSED METAL

0.05 MAX
ALL AROUND

NON-SOLDER MASK
DEFINED
(PREFERRED)

METAL UNDER
SOLDER MASK

SOLDER MASK
OPENING

EXPOSED METAL

0.05 MIN
ALL AROUND

SOLDER MASK
DEFINED

SOLDER MASK DETAILS
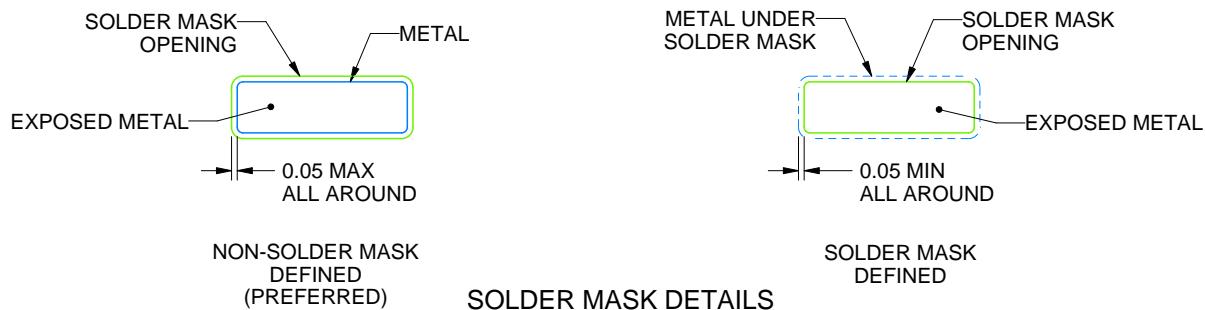
4220204/B   12/2023

NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

16X (1.5)

SYMM

1

16X (0.45)

(R0.05) TYP

16

SYMM

14X (0.65)

8

9

(5.8)
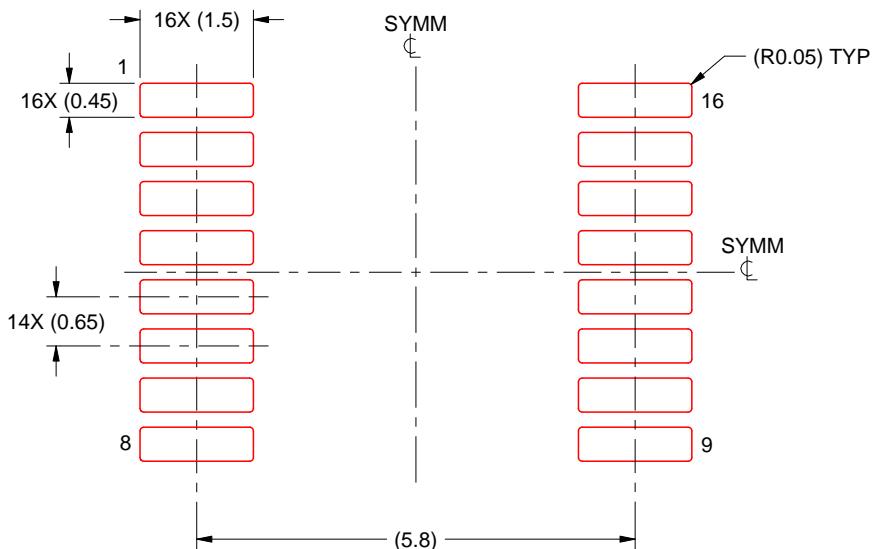
SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE: 10X

4220204/B   12/2023

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate
   design recommendations.
9. Board assembly site may have different recommendations for stencil design.